



GL M21R50FA9FD

Silicon N-Channel Power MOSFET Integrated FRD

General Description

GLM21R50FA9FD, the silicon N-channel Enhanced VDMOSFET, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-220F, which accords with the RoHS standard.

Features

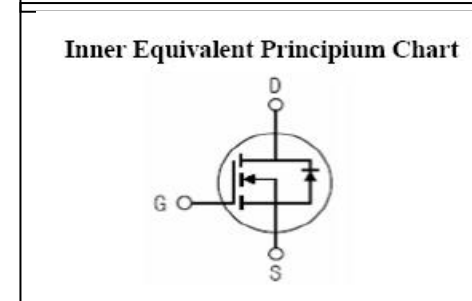
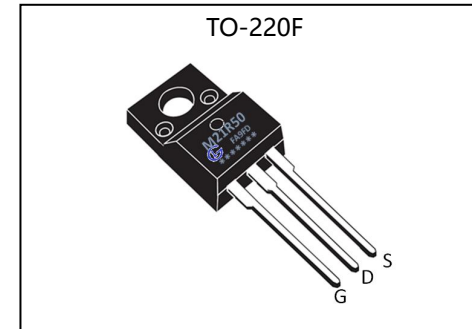
- Fast Switching
- Low ON Resistance($R_{dson}0.23\Omega$)
- Low Gate Charge (Typical Data:63nC)
- Low Reverse transfer capacitances(Typical:25pF)
- 100% Single Pulse avalanche energy Test

Applications

- Power switch circuit of adaptor and charger

Absolute (Tc=25°C unless otherwise specified)

V_{DSS}	500	V
I_D	21	A
$P_D(T_C=25^\circ C)$	55	W
$R_{DS(ON).TYP.}$	0.23	Ω



Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	500	V
I_D	Continuous Drain Current	21	A
	Continuous Drain Current $T_C=100^\circ C$	13	A
I_{DM}^{a1}	Pulsed Drain Current	84	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	1500	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	90	mJ
I_{AR}^{a1}	Avalanche Current	4.3	A
dv/dt^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	55	W
	Derating Factor above 25°C	0.44	W/°C
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T_L	Maximum Temperature for Soldering	300	°C

Caution Stresses greater than those in the "Absolute Maximum Ratings" may cause permanent damage to the device

Thermal Characteristics

Symbol	Parameter	Rating	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.27	°C/ W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	100	°C/ W



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Electrical Characteristics (Tc= 25°C unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	500	--	--	V
ΔBV _{DSS} /ΔT _J	Bvdss Temperature Coefficient	I _D =250uA, Reference 25°C	--	0.5	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} =500V, V _{GS} =0V, T _a =25°C	--	--	10	μA
		V _{DS} =400V, V _{GS} =0V, T _a =125°C	--	--	100	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} = +30V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} = -30V	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =10.5A	--	0.23	0.28	Ω
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	3.0	--	5.0	V
g _{fs}	Forward Trans conductance	V _{DS} =20V, I _D =10.5A	12	21	--	S
Pulse width < 380μs; duty cycle < 2%.						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V f=1.0MHz	--	2860	--	pF
C _{oss}	Output Capacitance		--	280	--	
C _{rss}	Reverse Transfer Capacitance		--	25	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =21A, V _{DD} =250V V _{GS} =10V, R _g =12Ω	--	33	--	ns
t _r	Rise Time		--	75	--	
t _{d(OFF)}	Turn-Off Delay Time		--	180	--	
t _f	Fall Time		--	83	--	
Q _g	Total Gate Charge	I _D =21A, V _{DD} =250V V _{GS} =10V	--	63	--	nC
Q _{gs}	Gate to Source Charge		--	14	--	
Q _{gd}	Gate to Drain ("Miller") Charge		--	24	--	



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Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_{SD}	Continuous Source Current (Body Diode)		--	--	21	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	84	A
V_{SD}	Diode Forward Voltage	$I_S=21A, V_{GS}=0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=21A, T_J=25^\circ C$	--	105	200	ns
Q_{rr}	Reverse Recovery Charge	$di_f/dt=100A/\mu s, V_{GS}=0V$	--	315	--	nC

a1: Repetitive rating; pulse width limited by maximum junction temperature

a2: $L=10mH, I_D=17.3A, \text{Start } T_J=25^\circ C$

a3: $I_{SD}=21A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_J=25^\circ C$



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Characteristics Curves

Fig. 1. Output Characteristics @ 25°C

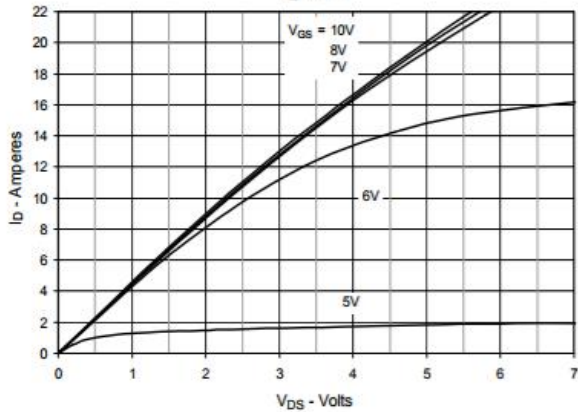


Fig. 2. Extended Output Characteristics @ 25°C

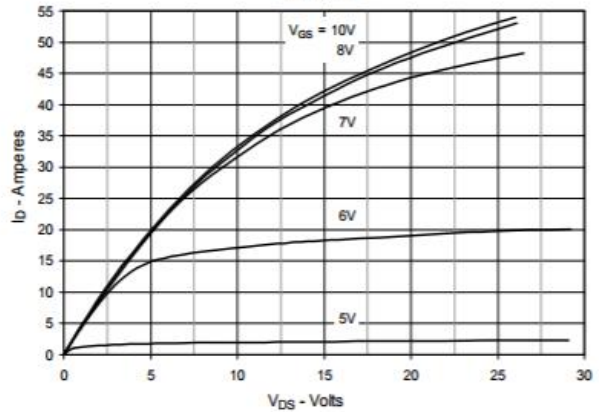


Fig. 3. Output Characteristics @ 125°C

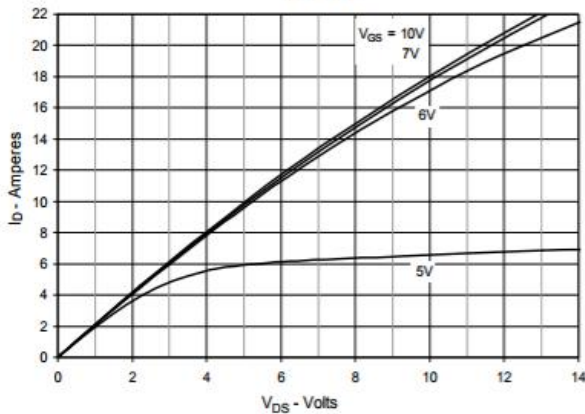


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 11\text{A}$ Value vs. Junction Temperature

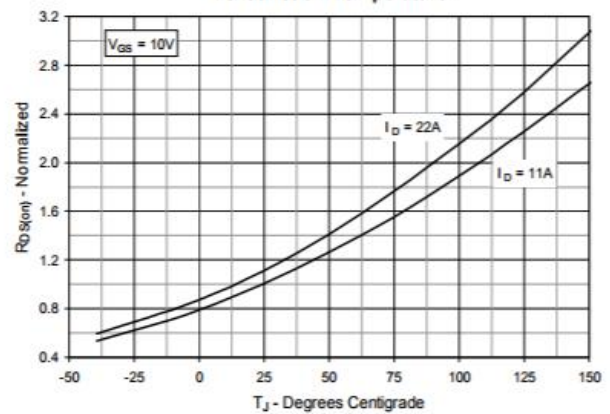


Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 11\text{A}$ Value vs. Drain Current

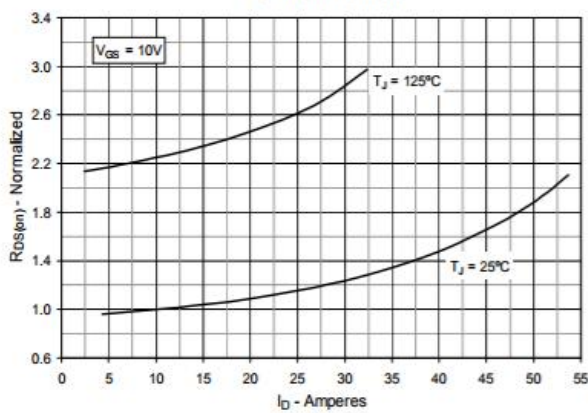
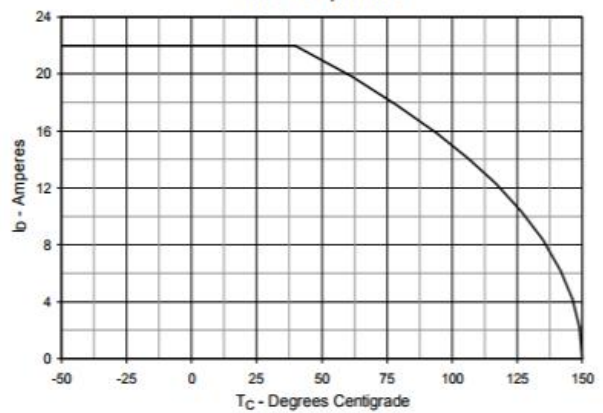


Fig. 6. Maximum Drain Current vs. Case Temperature





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Fig. 7. Input Admittance

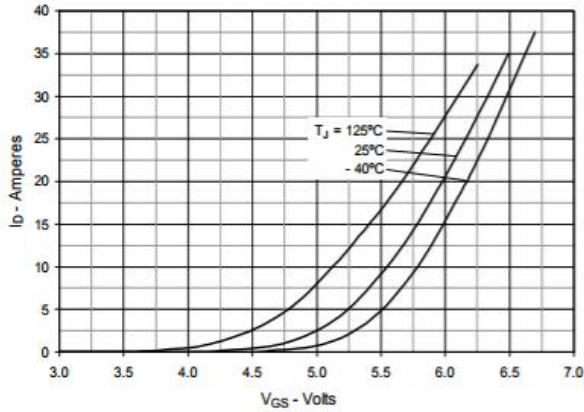


Fig. 8. Transconductance

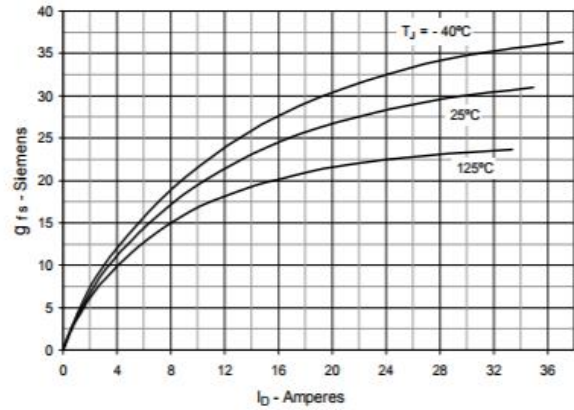


Fig. 9. Forward Voltage Drop of Intrinsic Diode

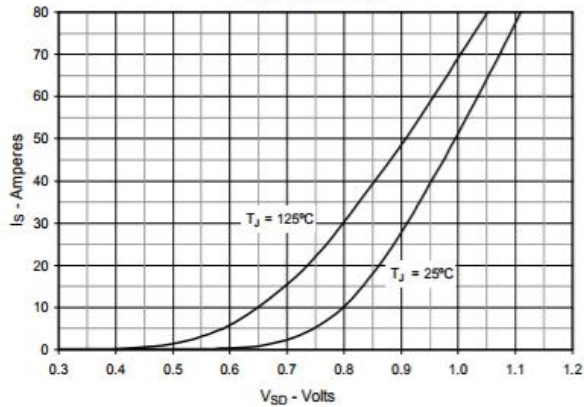


Fig. 10. Gate Charge

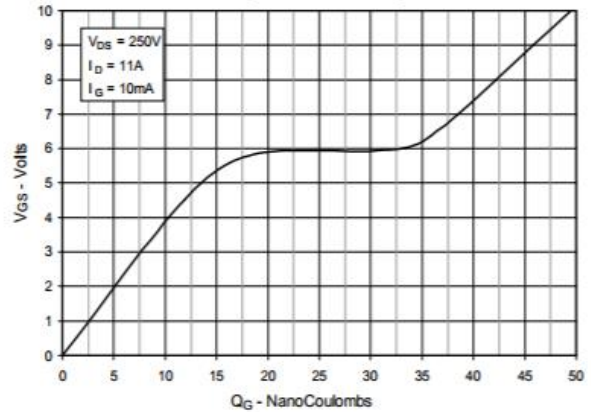


Fig. 11. Capacitance

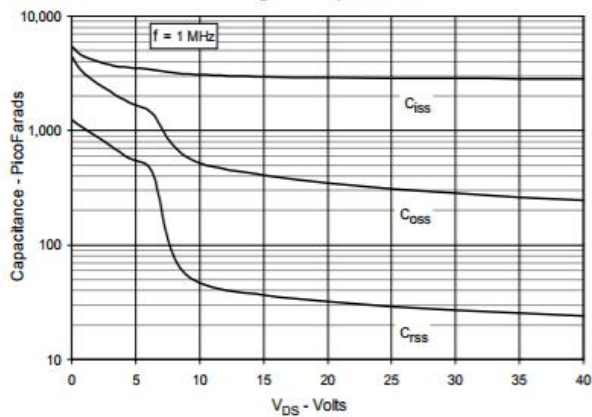
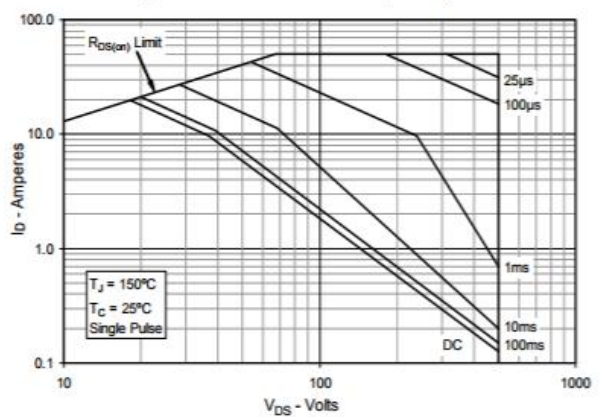


Fig. 12. Forward-Bias Safe Operating Area





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Fig. 13. Maximum Transient Thermal Impedance

